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**Applicant(s)/Patent Under Reexamination**  
WANG, JIAN

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| Art Unit | 2872 |
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Chapel, Derek S

## INTERNATIONAL CLASSIFICATION

|   |                    |   |   |         |                           |                        |
|---|--------------------|---|---|---------|---------------------------|------------------------|
| Derek S. Chapel<br><i>DSC</i><br>(Assistant Examiner)   | 6/8/2007<br>(Date) | <br>(Primary Examiner) | ARNEL LAVARIAS<br>PRIMARY PATENT EXAMINER<br>(Date) | 6/18/07 | O.G. Print Claim(s)<br>42 | O.G. Print Figure<br>4 |
| <br>(Legal Instruments Examiner) | 6/13/07<br>(Date)  |   |   |         |                           |                        |